

Laboratoire de Physique Nucléaire et de Hautes Energies

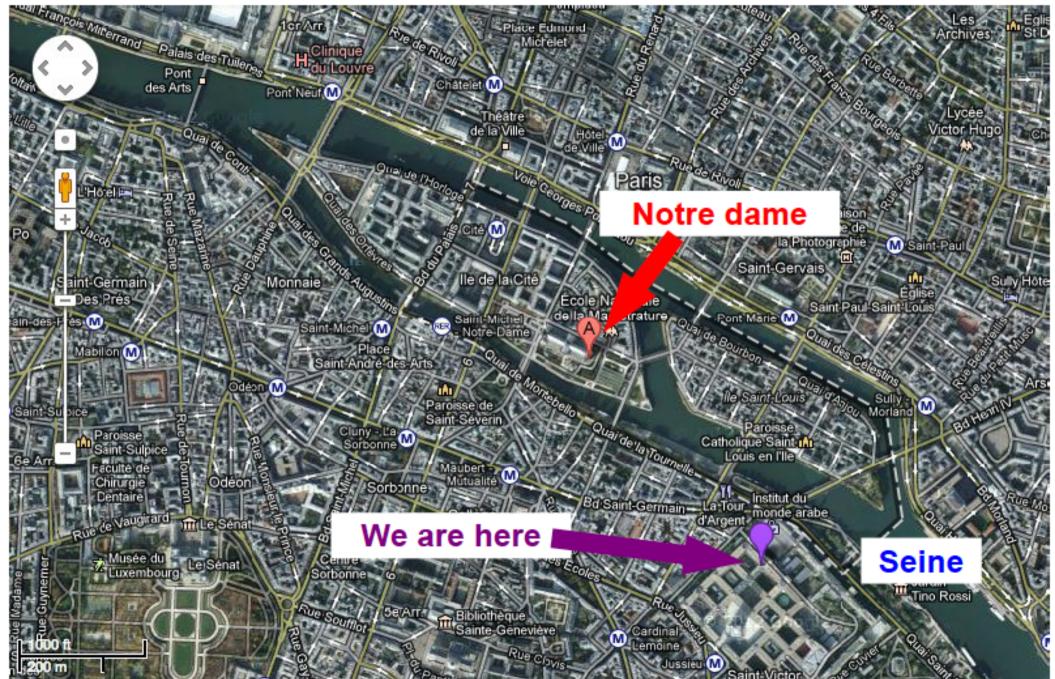
Mixed research unit (UMR) of Institut National de Physique Nucléaire et de Physique de Particules (IN2P3 CNRS) and Pierre et Marie Curie university (UPMC) and Paris Diderot university.





Where we are





LPNHE ATLAS Group

- G. Calderini (Group Leader)
- T. Beau (Staff Res.)
- M. Bomben (Post-doc)
- J. Chauveau (Prof)
- O. Davignon (PhD)
- A. Demilly (PhD)
- S. De Cecco (Staff Res.)
- F. Derue (Staff Res.)
- M.W. Krasny (Staff Res.)
- M. Kuna (Post-doc)
- D. Lacour (Staff Res.)
- B. Laforge (Prof)
- S. Laplace (Staff Res.)
- G. Lefebvre (PhD)
- B. Malaescu (Staff Res.)
- G. Marchiori (Staff Res.)
- N. Méric-Chrétien (PhD)
- I. Nikolic-Audit (Staff Res.)

- J. Ocariz (Prof)
- S. Pirès (Stage)
- C. Rangel-Smith (PhD)
- M. Ridel (Staff Res.)
- L. Roos (Staff Res.)
- Ph. Schwemling (Prof)
- T. Théveneaux-Pelzer (PhD)
- H. Torres (PhD)
- S. Trincaz-Duvoid (Staff Res)
- F. Vannucci (Prof)
- L. Yao (PhD)
- F. Crescioli
- D. Laporte
- Y. Orain,
- J.F. Genat,
- O. Ledortz
- L. Martin,
- V. Mendoza

People with implications in Si sensors and FTK

Giovanni Calderini – Director of research

in IAPP

- Former BaBar tracker project leader
- Planar pixels for ATLAS upgrade

Giovanni Marchiori – Researcher

Experience in Silicon detectors

Marco Bomben – Post-doc

- Experience in Silicon detectors
- ATLAS pixel test beam coordinator

Jacques Chauveau – Professor UPMC

Experience in Silicon detectors

Francesco Crescioli – Research Engineer

FTK experience

Jean-Francois Genat – Research Engineer

Experience in chip design

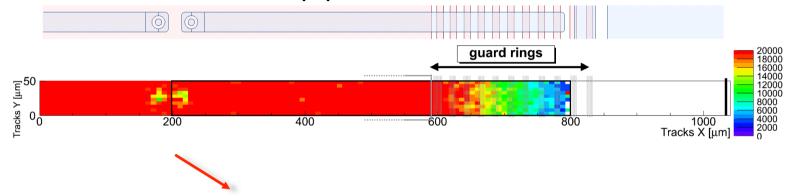
Olivier Le Dortz – Research Engineer

FPGA and perif. electronics experience

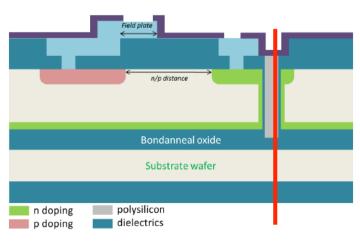
in IAPP

Sensors

- Contribution to ATLAS IBL
 - Simulations (Silvaco)
 - pixel-over-guard rings design
 - several n-in-n and n-in-p productions



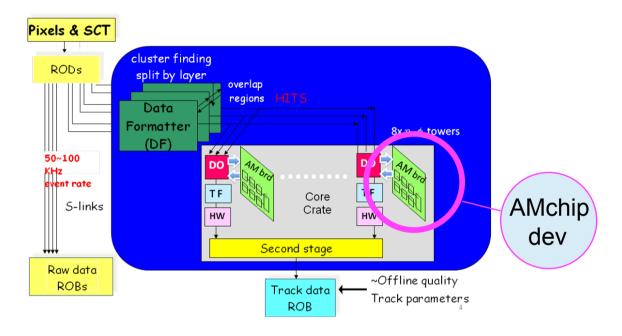
- Edgeless planar sensors (FBK-LPNHE)
 - Aim to phase-II ID (mid-outer layers)
 - Reduced dead area at periphery (~100 μm)
 - Sensors designed & simulated via TCAD
 - Tests started in our clean room
 - Next: CCE at periphery w/ laser, sources, beams

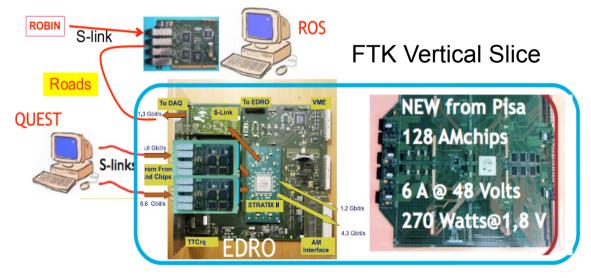


Cut line

FTK experience

Hardware



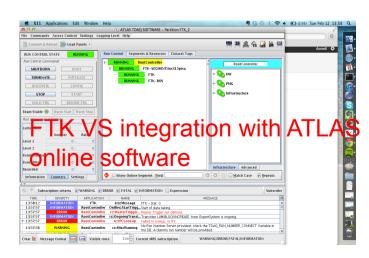


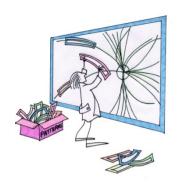
Software

FTK simulation & data preparation software

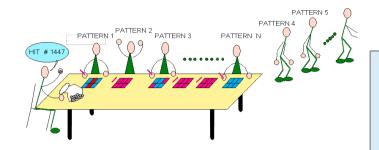
FTKSim
Pattern generator
from data & constants

FTKSim in ATHENA
JobOptions for trigger
studies





Associative Memory ~ AMchip



AMchip-based associative memory device first used in CDF (Amchip03).

AMchip03

- .6-layers patterns @ 18-bit
- .~5kpatt/chip
- .40 MHz

Used by FTK VS The associative memory is the core component of the pattern recognition stage of FTK

Performs the higly demanding task of coarse tracks finding in the full event.

The associative memory hardware is based on a custom made ASIC: AMchip

FTK needs more advanced technology:

AMchip04

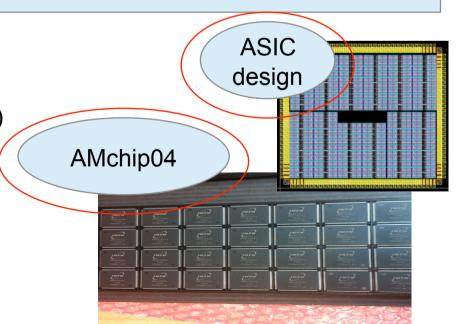
8-layers @ 15-bit (configurable3-7 bit w/ ternary logic)

- .~8kpatt/chip
- .100 MHz

AMchip05

- ·High speed serial I/O
- .~32kpatt/chip
- Stream merge function

Design phase



LPNHE activities in FTK/IAPP

- Development of a low-noise alimentation framework for radiation damaged ATLAS sensors (collaboration with CAEN)
- Test-stand development for FTK board validation and commissioning
 - AMchip tests
 - Boards tests
 - Integration HW/SW